

<b>Notice of References Cited</b>	Application/Control No. 10/694,017		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Chen-Wen Jiang		Art Unit 3744	Page 1 of 1

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*	B	US-2004/0123616 A1	07-2004	Lee et al.	062/271
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**NON-PATENT DOCUMENTS**

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